TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ( $L^2$ - $\pi$ -MOSV)

## 2SK2267

# Chopper Regulator, DC-DC Converter and Motor Drive Applications

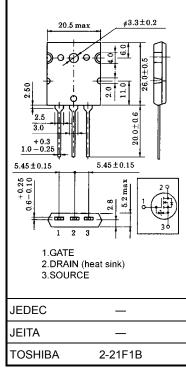
• 4-V gate drive

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & : R_{DS}\ (ON) = 8\ m\Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & : |Y_{fs}| = 60\ S\ (typ.) \\ \bullet & Low\ leakage\ current & : I_{DSS} = 100\ \mu A\ (max)\ (V_{DS} = 60\ V) \\ \bullet & Enhancement\ mode & : V_{th} = 0.8 \sim 2.0\ V\ (V_{DS} = 10\ V,\ I_D = 1\ mA) \end{array}$ 

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	60	V
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		$V_{DGR}$	60	V
Gate-source voltage		V <sub>GSS</sub>	±20	V
Drain current	DC (Note 1)	$I_{D}$	60	Α
Diam current	Pulse (Note 1)	$I_{DP}$	240	Α
Drain power dissipatio	n (Tc = 25°C)	$P_{D}$	150	W
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	1054	mJ
Avalanche current		I <sub>AR</sub>	60	Α
Repetitive avalanche	energy (Note 3)	E <sub>AR</sub>	15	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C

Unit: mm



Weight: 9.75 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	0.833	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	35.7	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD}$  = 25 V,  $T_{ch}$  = 25°C (initial), L = 398  $\mu$ H,  $R_{G}$  = 25  $\Omega$ ,  $I_{AR}$  = 60 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.

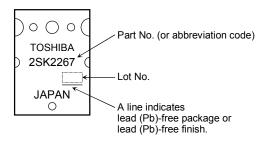
## **Electrical Characteristics (Ta = 25°C)**

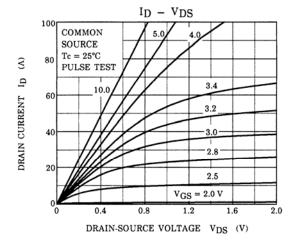
Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Drain cut-off cu	rent	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V		_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	60	_	_	V
Gate threshold v	roltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	0.8	_	2.0	V
Danier ON inter-		0	V <sub>GS</sub> = 4 V, I <sub>D</sub> = 30 A		12	15	- mΩ
Drain-source ON resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		8	11		
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 30 A	40	60	_	S
Input capacitano	е	C <sub>iss</sub>		_	5400	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	920	_	pF
Output capacitance		Coss			2600	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} = \frac{10V}{0V}$ $V_{GS} = \frac{10}{0V}$ $V_{DD} = 30V$ $V_{DD} = 30V$ $V_{DD} = 30V$ $Duty \le 1\%, t_{W} = 10 \mu s$	_	30	_	
	Turn-on time	t <sub>on</sub>		_	60	_	nc
	Fall time	t <sub>f</sub>		_	65	_	ns
	Turn-off time	t <sub>off</sub>			220	l	
Total gate charg plus gate–drain)			_	170	_	nC	
Gate-source charge		Q <sub>gs</sub>	V <sub>DD</sub> ≈ 48 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 60 A		110		_
Gate-drain ("miller") charge		$Q_{gd}$		_	60		

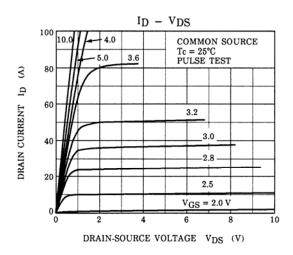
## Source-Drain Ratings and Characteristics (Ta = 25°C)

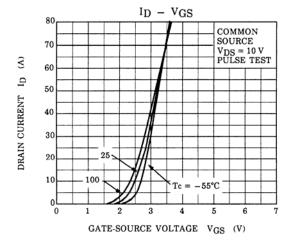
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	-	60	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	240	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 60 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 60 A, V <sub>GS</sub> = 0 V	1	150	1	ns
Reverse recovered charge	Q <sub>rr</sub>	dl <sub>DR</sub> / dt = 50 A / μs	_	0.3	_	μC

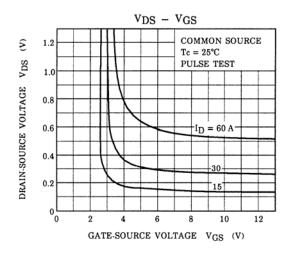
## Marking

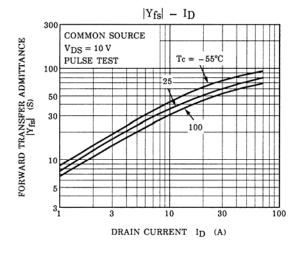


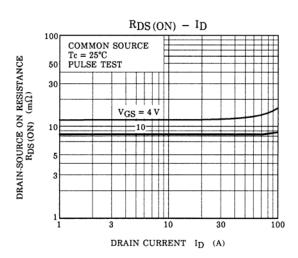


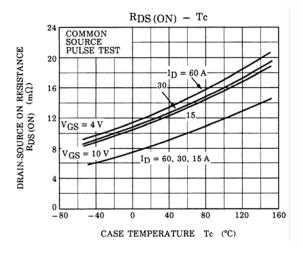


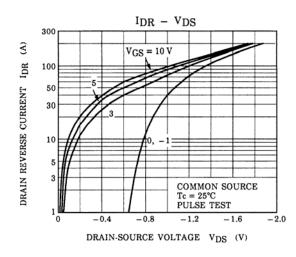


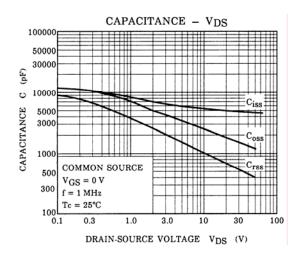


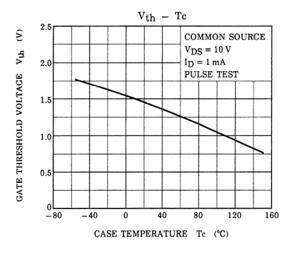


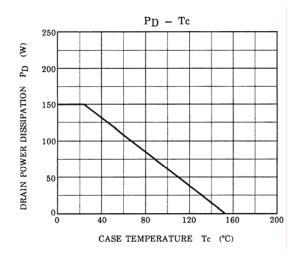


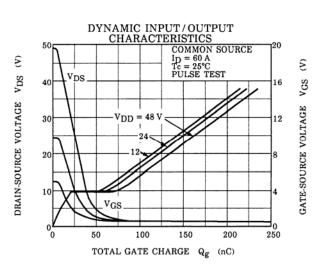


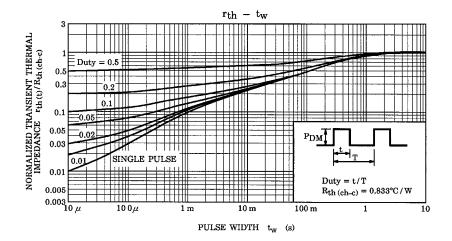


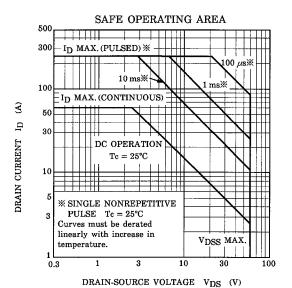


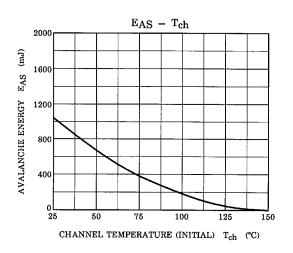


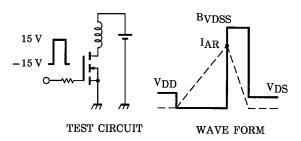












$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= 25~\text{V},~L = 398~\mu H \end{aligned} \qquad EAS &= \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{BVDSS}{BVDSS - VDD} \right) \end{aligned}$$

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